

ESD Protection Diode

27 V Dual Line Automotive Bus Protector

NUP2125, SZNUP2125

The SZ/NUP2125 has been designed to protect both CAN and LIN transceivers from ESD and other harmful transient voltage events. This device provides bidirectional protection for each data line with a single compact SC-70 (SOT-323) package, giving the system designer a low cost option for improving system reliability and meeting stringent EMI requirements.

Features

- 200 W Peak Power Dissipation per Line (8/20 μ s Waveform)
- Diode Capacitance Matching
- Low Reverse Leakage Current (< 100 nA)
- IEC Compatibility:
 - IEC 61000-4-2 (ESD): Level 4
 - IEC 61000-4-4 (EFT): 50 A – 5/50 ns
 - IEC 61000-4-5 (Lighting) 3.0 A (8/20 μ s)
- ISO 7637-1, Nonrepetitive EMI Surge Pulse 2, 8.0 A (1/50 μ s)
- ISO 7637-3, Repetitive Electrical Fast Transient (EFT) EMI Surge Pulses, 50 A (5/50 ns)
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These are Pb-Free Devices

Applications

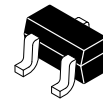
- Automotive Networks
 - ♦ CAN / CAN-FD
 - ♦ Low and High-Speed CAN
 - ♦ Fault Tolerant CAN
 - ♦ LIN

MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Rating	Max	Unit
PPK	Peak Power Dissipation, 8/20 μ s Double Exponential Waveform (Note 1)	200	W
T_J, T_{stg}	Junction and Storage Temperature Range	-55 to +175	$^\circ\text{C}$
T_L	Lead Solder Temperature (10 s)	260	$^\circ\text{C}$
ESD	Human Body Model (HBM)	± 8.0	kV
	Machine Model (MM)	± 1.6	kV
	IEC 61000-4-2 Contact	± 30	kV
	IEC 61000-4-2 Air	± 30	kV
	ISO 10605 Contact (330 pF / 330 Ω)	± 30	kV
	ISO 10605 Contact (330 pF / 2 k Ω)	± 30	kV
I_{PP}	Maximum Peak Pulse Current, 8/20 μ s	3	A

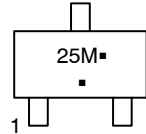
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Non-repetitive current pulse per Figure 1.

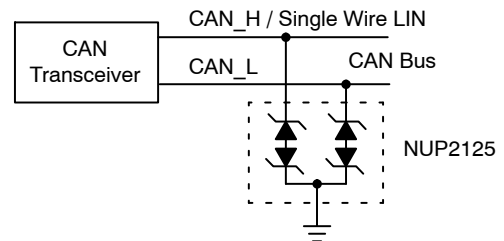
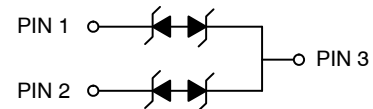


SC-70
CASE 419

MARKING DIAGRAM



25 = Specific Device Code
M = Date Code
▪ = Pb-Free Package
(Note: Microdot may be in either location)



ORDERING INFORMATION

Device	Package	Shipping†
NUP2125WTT1G	SC-70 (Pb-Free)	3000 / Tape & Reel
SZNUP2125WTT1G*		
NUP2125WTT3G		10000 / Tape & Reel
SZNUP2125WTT3G*		

† For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, [BRD8011/D](#).

* SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

ELECTRICAL CHARACTERISTICS

($T_A = 25\text{ }^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter
I_{PP}	Maximum Reverse Peak Pulse Current
V_C	Clamping Voltage @ I_{PP}
V_{RWM}	Working Peak Reverse Voltage
I_R	Maximum Reverse Leakage Current @ V_{RWM}
V_{BR}	Breakdown Voltage @ I_T
I_T	Test Current

*See Application Note AND8308/D for detailed explanations of data sheet parameters.

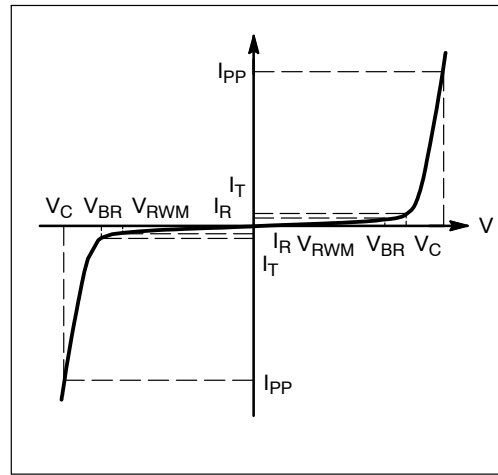


Figure 1. Bi-Directional

ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^{\circ}\text{C}$, unless otherwise specified)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
V_{RWM}	Reverse Working Voltage	(Note 2)	24	–	–	V
V_{BR}	Breakdown Voltage	$I_T = 1\text{ mA}$ (Note 3)	27	28.5	32	V
I_R	Reverse Leakage Current	$V_{RWM} = 24\text{ V}$	–	15	100	nA
V_C	Clamping Voltage	IEC61000-4-2, +/- 8 kV Contact	See Figures 8–9			
V_C	Clamping Voltage TLP (See Figures 12–13) (Note 6)	ITLP = 4 A ITLP = 8 A ITLP = 16 A ITLP = 20 A	– – – –	42 43 56 69	– – – –	V
V_C	Clamping Voltage 8/20 s Waveform (See Figures 6–7)	IPP = 1 A IPP = 13 A	– –	33.4 44.0	36.6 50.0	V
R_{dyn}	Dynamic Resistance	TLP Pulse	–	0.94	–	Ω
C_J	Capacitance	$V_R = 0\text{ V}$, $f = 1\text{ MHz}$ (Line to GND)	–	7.0	10	pF
		$V_R = 5\text{ V}$, $f = 1\text{ MHz}$ (Line to GND)	–	4.5	6.0	pF
		$V_R = 5\text{ V}$, $f = 1\text{ MHz}$ (Line to GND), $T_A = +150\text{ }^{\circ}\text{C}$	–	5.0	–	pF
ΔC	Diode Capacitance Matching	$V_R = 0\text{ V}$, 5 MHz (Note 5)	–	0.26	2	%
I_L	Insertion Loss	$f = 1\text{ GHz}$ $f = 5\text{ GHz}$	–	8.7 1.7	–	dB
R_L	Return Loss	$f = 1\text{ GHz}$ $f = 5\text{ GHz}$	–	1.5 1.0	–	dB

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- Surge protection devices are normally selected according to the working peak reverse voltage (V_{RWM}), which should be equal or greater than the DC or continuous peak operating voltage level.
- V_{BR} is measured at pulse test current I_T .
- Pulse waveform per Figure 6.
- ΔC is the percentage difference between C_J of lines 1 and 2 measured according to the test conditions given in the electrical characteristics table.
- ANSI/ESD STM5.5.1 – Electrostatic Discharge Sensitivity Testing using Transmission Line Pulse (TLP) Model. TLP conditions: $Z_0 = 50\text{ }\Omega$, $t_p = 100\text{ ns}$, $t_r = 4\text{ ns}$, averaging window; $t_1 = 30\text{ ns}$ to $t_2 = 60\text{ ns}$.

TYPICAL PERFORMANCE CURVES

($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

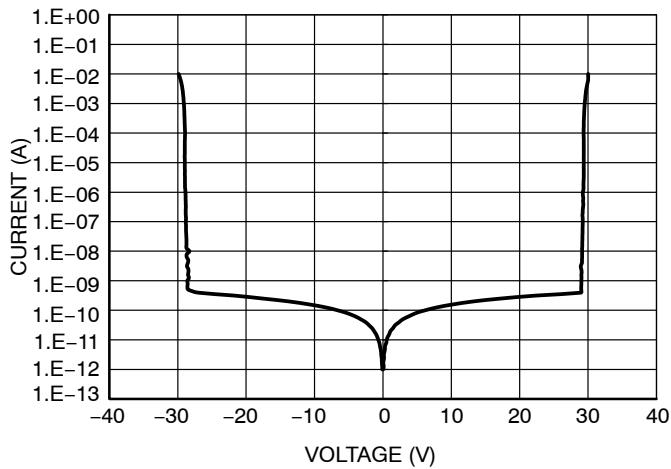


Figure 2. IV Characteristics

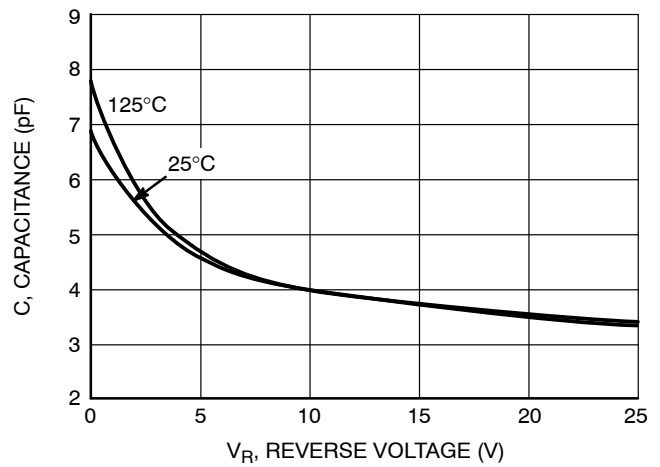


Figure 3. CV Characteristics

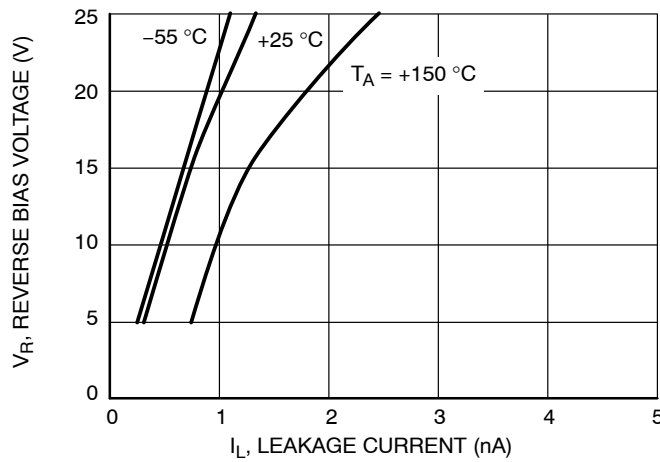


Figure 4. I_R vs. Temperature Characteristics

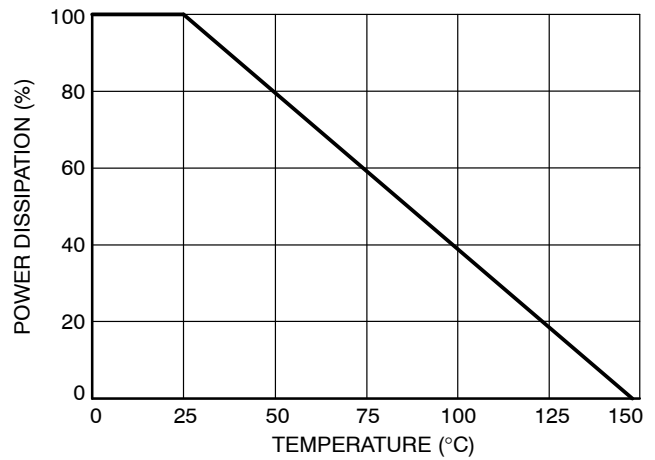


Figure 5. Steady State Power Derating

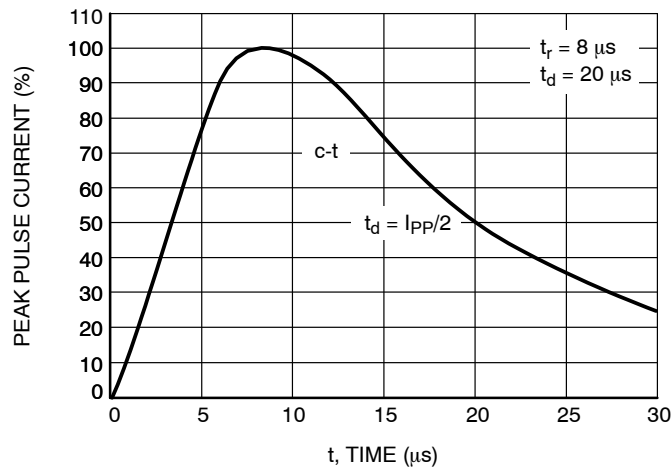


Figure 6. Pulse Waveform (8/20 μs)

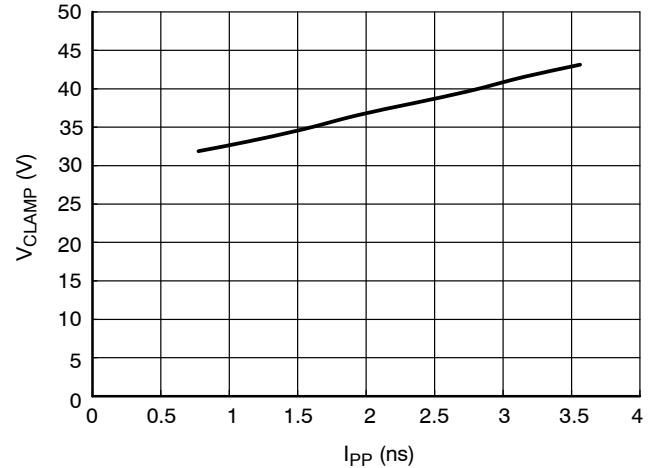


Figure 7. Clamping Voltage vs. Peak Pulse Current (8/20 μs)

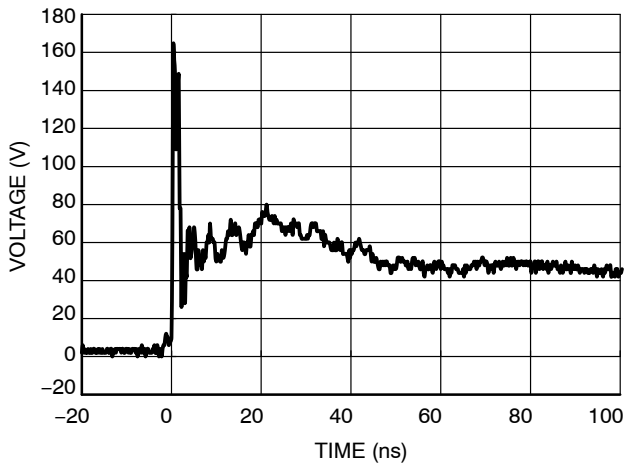


Figure 8. IEC61000-4-2 +8 kV Contact

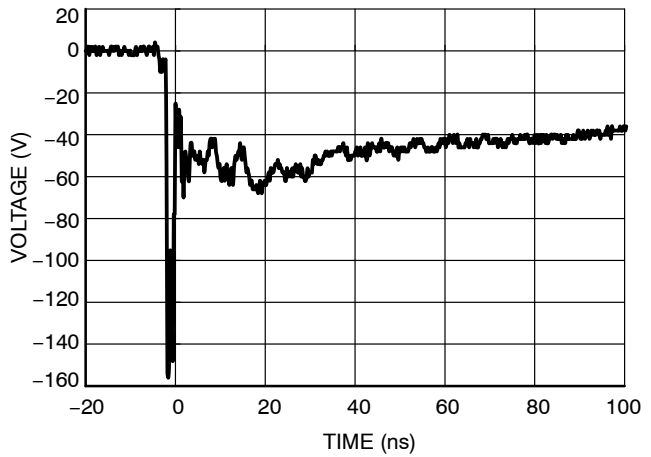


Figure 9. IEC61000-4-2 -8 kV Contact

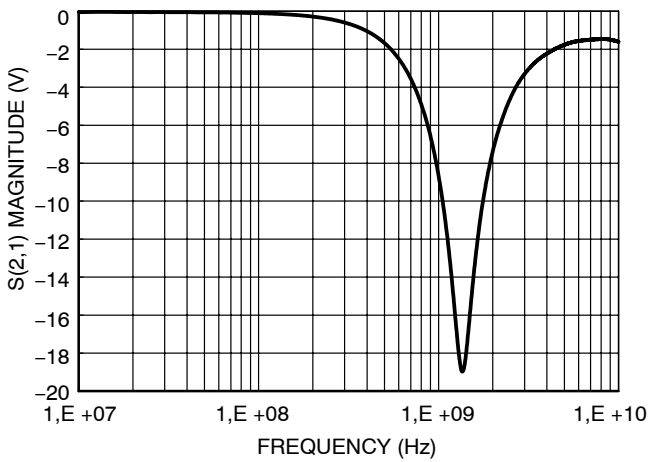


Figure 10. Typical Insertion Loss

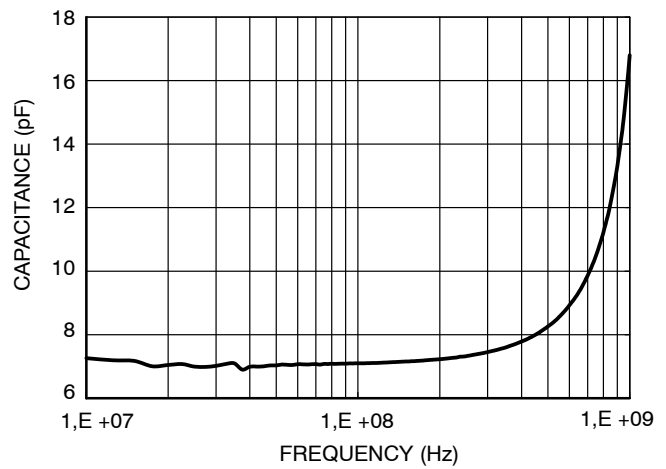


Figure 11. Typical Capacitance vs. Frequency

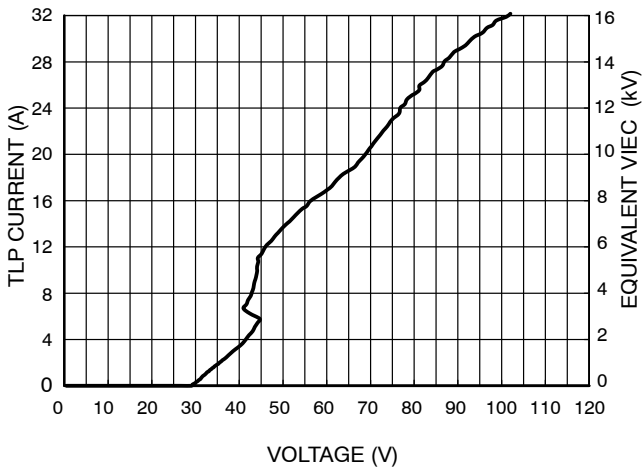


Figure 12. Positive TLP IV Curve

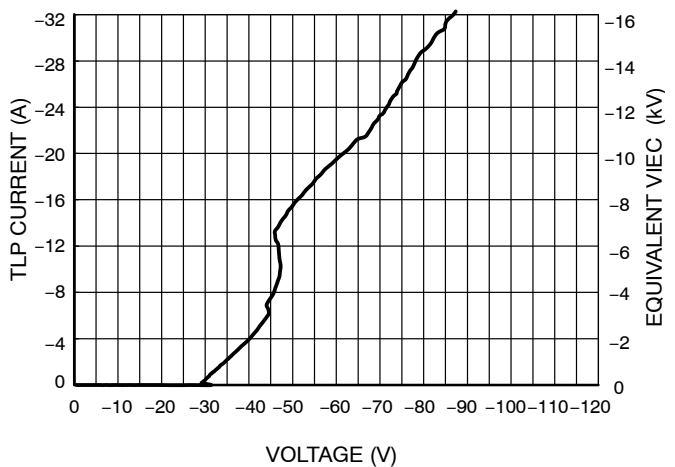


Figure 13. Negative TLP IV Curve

Surge Protection Diode Circuit

Surge protection diodes provide protection to a transceiver by clamping a surge voltage to a safe level. Surge protection diodes have high impedance below and low impedance above their breakdown voltage. A surge protection Zener diode has its junction optimized to absorb the high peak energy of a transient event, while a standard Zener diode is designed and specified to clamp a steady state voltage.

Figure 14 provides an example of a dual bidirectional surge protection diode array that can be used for protection with the high-speed CAN network. The bidirectional array is created from four identical Zener TVS diodes. The clamping voltage of the composite device is equal to the breakdown voltage of the diode that is reversed biased, plus the diode drop of the second diode that is forward biased.

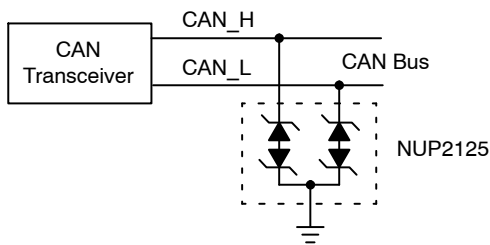


Figure 14. High-Speed and Fault Tolerant CAN Surge Protection Circuit

ESD Voltage Clamping

For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000-4-2 waveform. Since the IEC61000-4-2 was written as a pass/fail spec for larger systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage at the device level. **onsemi** has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how to create these screenshots and how to interpret them please refer to AND8307/D.

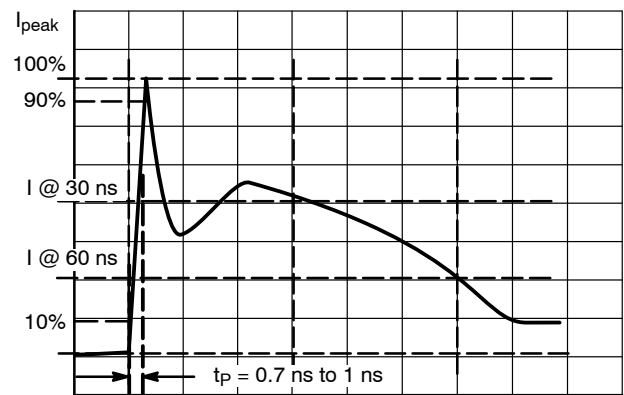


Figure 15. IEC61000-4-2 Current Waveform

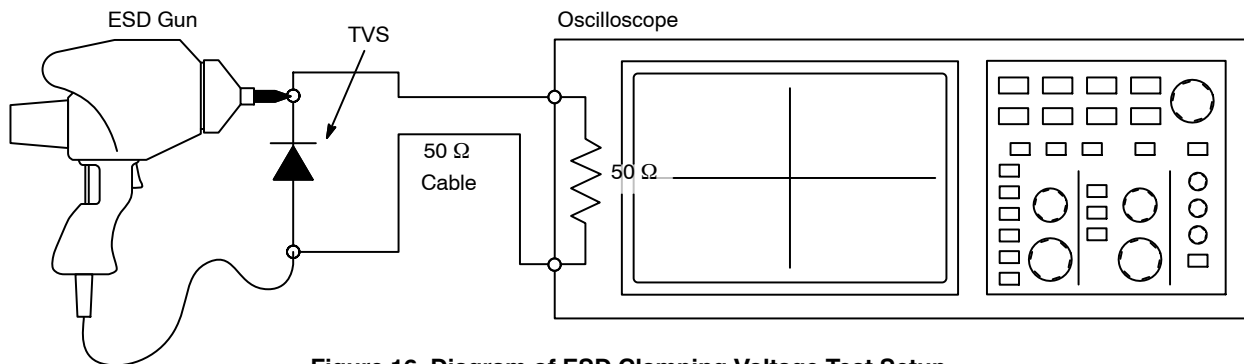


Figure 16. Diagram of ESD Clamping Voltage Test Setup

NUP2125, SZNUP2125

Transmission Line Pulse (TLP) Measurement

TLP provides current versus voltage (I-V) curves in which each data point is obtained from a 100 ns long rectangular pulse from a charged transmission line. A simplified schematic of a typical TLP system is shown in Figure 17. TLP I-V curves of ESD protection devices accurately demonstrate the product's ESD capability because the 10s of

amps current levels and under 100 ns time scale match those of an ESD event. This is illustrated in Figure 18 where an 8 kV IEC 61000-4-2 current waveform is compared with TLP current pulses at 8 A and 16 A. A TLP I-V curve shows the voltage at which the device turns on as well as how well the device clamps voltage over a range of current levels.

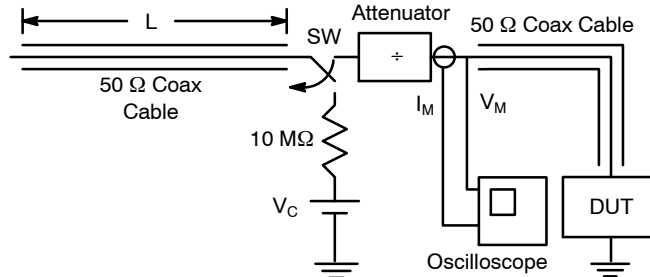


Figure 17. Basic TLP System

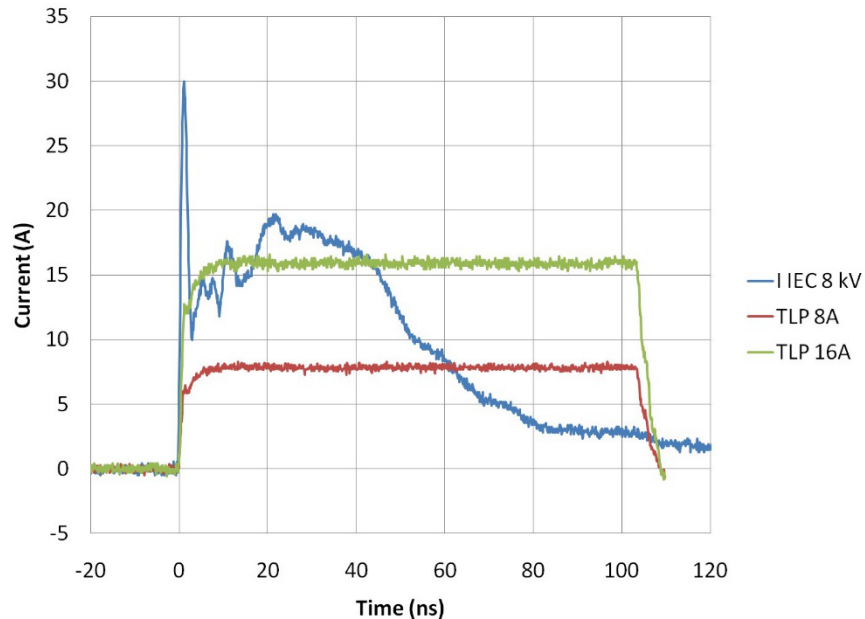


Figure 18. Comparison Between 8 kV IEC 61000-4-2 and 8 A and 16 A TLP Waveforms

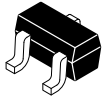
NUP2125, SZNUP2125

REVISION HISTORY

Revision	Description of Changes	Date
9	Updated document layout to align with NUP2205/D, including removal of Flammability Rating from page 1 and relocation of Ordering Information to page 1. Revised and expanded Maximum Ratings and Electrical Characteristics tables (added R _{dyn} , IL, RL; updated TLP data). Updated figure titles and replaced selected plots with data derived from the provided Excel files. Added IEC/ISO test conditions, updated clamping-voltage values, and introduced extended characterization sections (IEC ESD ± 8 kV, TLP curves, insertion loss, capacitance vs. frequency). Performed structural cleanup, removed obsolete content, aligned terminology, corrected IL and RL sign convention, and updated Figures 10 and 11.	5/7/2026

This document has undergone updates prior to the inclusion of this revision history table. The changes tracked here only reflect updates made on the noted approval dates.

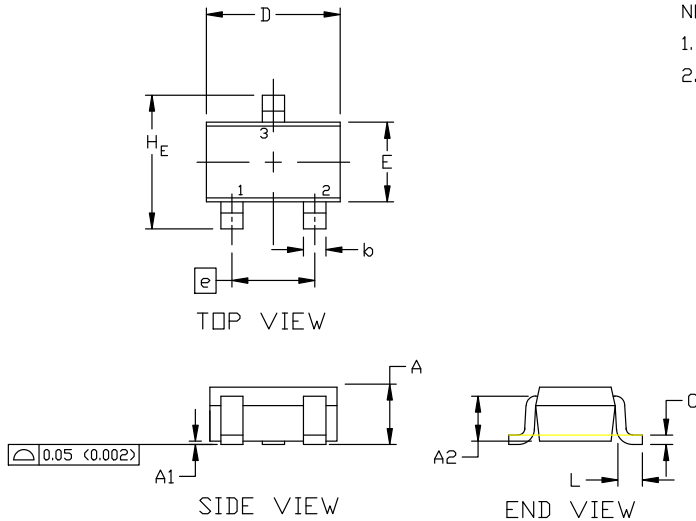




SCALE 4:1

SC-70 (SOT-323)
CASE 419
ISSUE R

DATE 11 OCT 2022

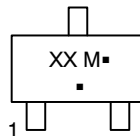


NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH

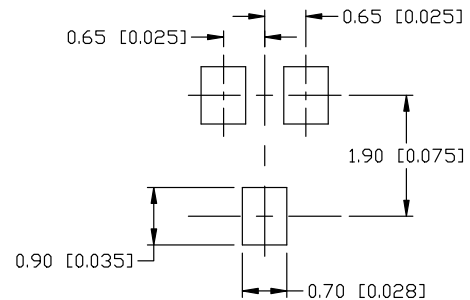
DIM	MILLIMETERS			INCHES		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	0.80	0.90	1.00	0.032	0.035	0.040
A1	0.00	0.05	0.10	0.000	0.002	0.004
A2	0.70 REF			0.028 BSC		
b	0.30	0.35	0.40	0.012	0.014	0.016
c	0.10	0.18	0.25	0.004	0.007	0.010
D	1.80	2.00	2.20	0.071	0.080	0.087
E	1.15	1.24	1.35	0.045	0.049	0.053
e	1.20	1.30	1.40	0.047	0.051	0.055
e1	0.65 BSC			0.026 BSC		
L	0.20	0.38	0.56	0.008	0.015	0.022
H _E	2.00	2.10	2.40	0.079	0.083	0.095

GENERIC
MARKING DIAGRAM



XX = Specific Device Code
M = Date Code
▪ = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.



* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

SOLDERING FOOTPRINT

STYLE 1:
CANCELLED

STYLE 2:
PIN 1. ANODE
2. N.C.
3. CATHODE

STYLE 3:
PIN 1. BASE
2. EMITTER
3. COLLECTOR

STYLE 4:
PIN 1. CATHODE
2. CATHODE
3. ANODE

STYLE 5:
PIN 1. ANODE
2. ANODE
3. CATHODE

STYLE 6:
PIN 1. EMITTER
2. BASE
3. COLLECTOR

STYLE 7:
PIN 1. BASE
2. EMITTER
3. COLLECTOR

STYLE 8:
PIN 1. GATE
2. SOURCE
3. DRAIN

STYLE 9:
PIN 1. ANODE
2. CATHODE
3. CATHODE-ANODE

STYLE 10:
PIN 1. CATHODE
2. ANODE
3. ANODE-CATHODE

STYLE 11:
PIN 1. CATHODE
2. CATHODE
3. CATHODE

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